



7/19/2012

**RELIABILITY MONITOR REPORT  
FOR**

**MFN 250V Bipolar CMOS DMOS (BCD250)**

**MAXIM Integrated Products**

**120 San Gabriel Dr.  
Sunnyvale, CA 94086**

**This Report was prepared by  
Maxim Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX14803CCM	MAX4802CQ1+
-------------	-------------

The calculated failure rate for devices using this process is:

**FAILURE RATE:    MTTF (YRS): 12588    QUANTITY: 160    FAILS: 0    FITS: 9.1**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25    °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

**Process Information:**

Process Description:            MFN 250V Bipolar CMOS DMOS (BCD250)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1115	MAX4802CQ1+	135C	500 HRS	80	0	NEE1HA111G
HIGH TEMP OP LIFE	1124	MAX14803CCM+	135C	312 HRS	80	0	NRSWD2007BA
<b>Total:</b>						<b>0</b>	

**FAILURE RATE:    MTTF (YRS): 12588    QUANTITY: 160    FAILS: 0    FITS: 9.1**